Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

IECQ Certificate No.: IECQ-L DEKRA 16.0002-04

CB Certificate No.: DEKRA-T5E-003

Schedule Number: IECQ-L DEKRA 16.0002-04-S **Rev No.:** 1 **Revision Date:** 2025/07/20 **Page** 1 **of** 1

Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

Description test	Standard	Remarks
Failure and material analysis of semiconductor IC (TEM / SEM / DUAL BEAM FIB)	JEDEC-C201, EIA-469, IEC62321, EN14582, ISO_29301, ISO/DIS 2549	Or customer specified test

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